



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Ohtani, et al. Art Unit : 2815
 Serial No. : 09/455,991 Examiner : Jose R. Diaz
 Filed : December 6, 1999
 Title : METHOD OF MANUFACTURING A SEMICONDUCTOR DEVICE HAVING
 TFTS WITH UNIFORM CHARACTERISTICS (AS AMENDED)

MAIL STOP RCE

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AL	Japan 07-066425 – English Abstract: DIALOG(R) File 347: JAPIO (2004); Accession No. 04773825 and family to U.S. Patent No. 5,534,716 (Desig. ID “AB”), U.S. Patent No. 6,194,254 (Desig. ID “AE”), U.S. Patent No. 6,482,686 (Desig. ID “AF”), U.S. Patent Application Publication No. US 2003/054595 A1 (Desig. ID “AA”), and U.S. Patent No. 5,616,506 (previously submitted).
AM	Japan 07-297125 – English Abstract: DIALOG(R) File 347: JAPIO (2005); Accession No. 05004525 and family to U.S. Patent No. 5,696,003 (Desig. ID “AC”) and U.S. Patent No. 5,821,562 (Desig. ID “AD”).

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Date: 8/29/05

Respectfully submitted,

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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-213002Application No.
09/455,991**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant
Ohtani, et al.Filing Date
December 6, 1999Group Art Unit
2815**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2003-0054595	03/20/2003	Takemura			10/21/2002
	AB	5,534,716	07/09/1996	Takemura			08/23/1994
	AC	5,696,003	12/09/1997	Makita et al.			12/16/1994
	AD	5,821,562	10/13/1998	Makita et al.			05/30/1995
	AE	6,194,254	02/27/2001	Takemura			03/28/1997
	AF	6,482,686	11/19/2002	Takemura			07/12/2000
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	AL	JP07-066425	10 MAR 1995	JAPAN			Abstract	
	AM	JP07-297125	10 NOV 1995	JAPAN			Abstract	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.